

32K × 8 ELECTRICALLY ERASABLE EPROM

GENERAL DESCRIPTION

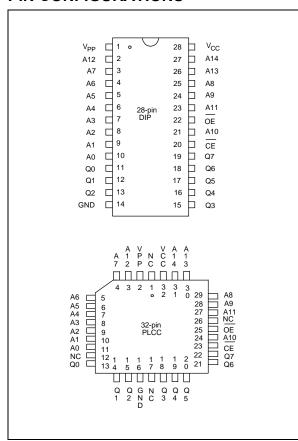
The W27E257 is a high-speed, low-power Electrically Erasable and Programmable Read Only Memory organized as 32768×8 bits that operates on a single 5 volt power supply. The W27E257 provides an electrical chip erase function. This part was the same EPROM Writer's utilities as the W27E256.

FEATURES

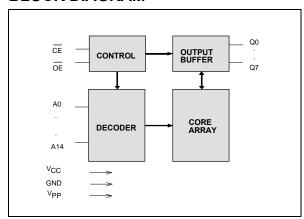
- High speed access time: 100/120/150 nS (max.)
- Read operating current: 15 mA (typ.)
- Erase/Programming operating current 1 mA (typ.)
- Standby current: 5 μA (typ.)
- Single 5V power supply

- +14V erase/+12V programming voltage
- Fully static operation
- All inputs and outputs directly TTL/CMOS compatible
- Three-state outputs
- Available packages: 28-pin 600 mil DIP and 32-pin PLCC

PIN CONFIGURATIONS



BLOCK DIAGRAM



PIN DESCRIPTION

SYMBOL	DESCRIPTION
A0-A14	Address Inputs
Q0-Q7	Data Inputs/Outputs
CE	Chip Enable
ŌĒ	Output Enable
Vpp	Program/Erase Supply Voltage
Vcc	Power Supply
GND	Ground
NC	No Connection



FUNCTIONAL DESCRIPTION

Read Mode

Like conventional UVEPROMs, the W27E257 has two control functions, both of which produce data at the outputs.

 $\overline{\text{CE}}$ is for power control and chip select. $\overline{\text{OE}}$ controls the output buffer to gate data to the output pins. When addresses are stable, the address access time (TACC) is equal to the delay from $\overline{\text{CE}}$ to output (TCE), and data are available at the outputs TOE after the falling edge of $\overline{\text{OE}}$, if TACC and TCE timings are met.

Erase Mode

The erase operation is the only way to change data from "0" to "1." Unlike conventional UVEPROMs, which use ultraviolet light to erase the contents of the entire chip (a procedure that requires up to half an hour), the W27E257 uses electrical erasure. Generally, the chip can be erased within 100 mS by using an EPROM writer with a special erase algorithm.

Erase mode is entered when VPP is raised to VPE (14V), VCC = VCE (5V), \overline{OE} = VIH (2V or above but lower than VCC), A9 = VHH (14V), A0 = VIL (0.8V or below but higher than GND), and all other address pins equal VIL and data input pins equal VIH. Pulsing \overline{CE} low starts the erase operation.

Erase Verify Mode

After an erase operation, all of the bytes in the chip must be verified to check whether they have been successfully erased to "1" or not. The erase verify mode automatically ensures a substantial erase margin. This mode will be entered after the erase operation if VPP = VPE (14V), $\overline{CE} = VIH$, and $\overline{OE} = VIH$

Program Mode

Programming is performed exactly as it is in conventional UVEPROMs, and programming is the only way to change cell data from "1" to "0." The program mode is entered when VPP is raised to VPP (12V), VCC = VCP (5V), $\overline{OE} = V_{IH}$, the address pins equal the desired address, and the input pins equal the desired inputs. Pulsing \overline{CE} low starts the programming operation.

Program Verify Mode

All of the bytes in the chip must be verified to check whether or not they have been successfully programmed with the desired data. Hence, after each byte is programmed, a program verify operation should be performed. The program verify mode automatically ensures a substantial program margin. This mode will be entered after the program operation if VPP = VPP (12V), $\overline{CE} = VIH$, and $\overline{OE} = VIL$.

Erase/Program Inhibit

Erase or program inhibit mode allows parallel erasing or programming of multiple chips with different data. When $\overline{CE} = VIH$, erasing or programming of non-target chips is inhibited, so that except for the \overline{CE} and \overline{OE} pins, the W27E257 may have common inputs.



Standby Mode

The standby mode significantly reduces VCC current. This mode is entered when $\overline{CE} = VIH$. In standby mode, all outputs are in a high impedance state, independent of \overline{OE} .

Two-line Output Control

Since EPROMs are often used in large memory arrays, the W27E257 provides two control inputs for multiple memory connections. Two-line control provides for lowest possible memory power dissipation and ensures that data bus contention will not occur.

System Considerations

EPROM power switching characteristics require careful device decoupling. System designers are interested in three supply current issues: standby current levels (IsB), active current levels (Icc), and transient current peaks produced by the falling and rising edges of $\overline{\text{CE}}$. Transient current magnitudes depend on the device output's capacitive and inductive loading. Two-line control and proper decoupling capacitor selection will suppress transient voltage peaks. Each device should have a 0.1 μ F ceramic capacitor connected between its Vcc and GND. This high frequency, low inherent-inductance capacitor should be placed as close as possible to the device. Additionally, for every eight devices, a 4.7 μ F electrolytic capacitor should be placed at the array's power supply connection between Vcc and GND. The bulk capacitor will overcome voltage slumps caused by PC board trace inductances.

TABLE OF OPERATING MODES

(VPP = 12V, VPE = 14V, VHH = 12V, VCP = 5V, X = VIH or VIL)

MODE	PINS						
	CE	OE	A0	A 9	Vcc	VPP	OUTPUTS
Read	VIL	VIL	Х	X	Vcc	Vcc	Dout
Output Disable	VIL	ViH	Χ	X	Vcc	Vcc	High Z
Standby (TTL)	Vih	Х	Χ	X	Vcc	Vcc	High Z
Standby (CMOS)	Vcc ±0.3V	Х	Χ	Х	Vcc	Vcc	High Z
Program	VIL	ViH	Х	X	VCP	VPP	DIN
Program Verify	ViH	VIL	Х	Х	VCP	VPP	Dout
Program Inhibit	ViH	ViH	Х	X	VCP	VPP	High Z
Erase	VIL	ViH	VIL	VPE	Vcc	VPE	DIH
Erase Verify	VIH	VIL	Χ	Х	Vcc	VPE	Dout
Erase Inhibit	ViH	ViH	Х	X	VCP	VPP	High Z
Product Identifier-manufacturer	VIL	VIL	VIL	Vнн	Vcc	Vcc	DA (Hex)
Product Identifier-device	VIL	VIL	VIH	Vнн	Vcc	Vcc	02 (Hex)



DC CHARACTERISTICS

Absolute Maximum Ratings

PARAMETER	RATING	UNIT
Ambient Temperature with Power Applied	-55 to +125	°C
Storage Temperature	-65 to +125	°C
Voltage on all pins with Respect to Ground Except VPP, A9 and Vcc pins	-0.5 to Vcc +0.5	V
Voltage on VPP Pin with Respect to Ground	-0.5 to +14.5	V
Voltage on A9 Pin with Respect to Ground	-0.5 to +14.5	V
Voltage on Vcc Pin with Respect to Ground	-0.5 to +7	V

Note: Exposure to conditions beyond those listed under Absolute Maximum Ratings may adversely affect the life and reliability of the device.

DC Erase Characteristics

(TA = 25° C $\pm 5^{\circ}$ C, Vcc = 5.0V $\pm 10\%$)

PARAMETER	SYM.	CONDITIONS	LIMITS		UNIT	
			MIN.	TYP.	MAX.	
Input Load Current	ILI	VIN = VIL or VIH	-10	-	10	μΑ
Vcc Erase Current	ICP	CE = VIL	-	-	30	mA
VPP Erase Current	IPP	CE = VIL	-	-	30	mA
Input Low Voltage	VIL	-	-0.3	-	0.8	V
Input High Voltage	ViH	-	2.4	-	5.5	V
Output Low Voltage (Verify)	Vol	IOL = 2.1 mA	-	ı	0.45	V
Output High Voltage (Verify)	Voн	Iон = -0.4 mA	2.4	ı	-	-
A9 Erase Voltage	VID	-	13.75	14	14.25	V
VPP Erase Voltage	VPE	-	13.75	14	14.25	V
Vcc Supply Voltage (Erase)	VCE	-	4.5	5.0	5.5	V

Note: Vcc must be applied simultaneously or before VPP and removed simultaneously or after VPP.

CAPACITANCE

(Vcc = 5V, TA = 25° C, f = 1 MHz)

PARAMETER	SYMBOL	CONDITIONS	MAX.	UNIT
Input Capacitance	CIN	VIN = 0V	6	pF
Output Capacitance	Соит	Vout = 0V	12	pF

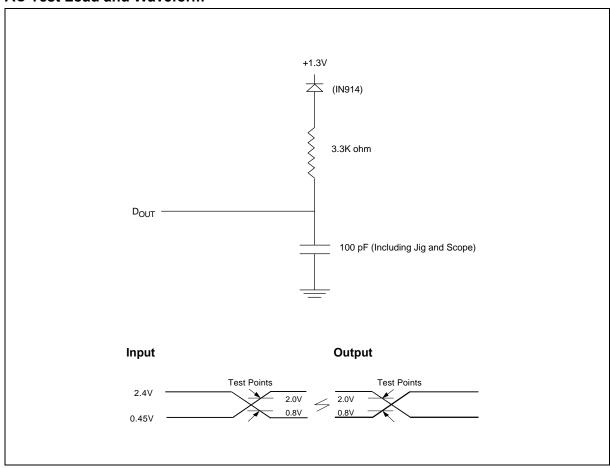


AC CHARACTERISTICS

AC Test Conditions

PARAMETER	CONDITIONS
Input Pulse Levels	0.45V to 2.4V
Input Rise and Fall Times	10 nS
Input and Output Timing Reference Level	0.8V/2.0V
Output Load	CL = 100 pF, IOH/IOL = -0.4 mA/2.1 mA

AC Test Load and Waveform





READ OPERATION DC CHARACTERISTICS

(Vcc = $5.0V \pm 10\%$, TA = 0 to 70° C)

(W27E257-10, S-10, K-10, P-10: Vcc, min. = 3.0V and max. = 5.5V)

PARAMETER	SYM.	CONDITIONS	LIMITS			UNIT
			MIN.	TYP.	MAX.	
Input Load Current	lu	VIN = 0V to VCC	-5	-	5	μΑ
Output Leakage Current	ILO	Vout = 0V to Vcc	-10	-	10	μΑ
Vcc Standby Current	ISB	CE = VIH	-	-	1.0	mA
	ISB1	CE = Vcc ±0.2V	-	5	100	μΑ
Vcc Operating Current	Icc	CE = VIL IOUT = 0 mA f = 5 MHz	-	-	30	mA
VPP Operating Current	IPP	VPP = VCC	-	-	100	μА
Input Low Voltage	VIL	-	-0.3	-	0.8	V
Input High Voltage	VIH	-	2.0	-	Vcc +0.5	V
Output Low Voltage	Vol	IOL = 2.1 mA	-	-	0.45	V
Output High Voltage	Vон	IOH = -0.4 mA	2.4	-	-	V
VPP Operating Voltage	VPP	-	Vcc -0.7	-	Vcc	V

READ OPERATION AC CHARACTERISTICS

(Vcc = 5.0V $\pm 10\%$, TA = 0 to 70° C)

PARAMETER	SYM.	W27E	257-10	57-10 W27E257-12		W27E257-15		UNIT
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Read Cycle Time	Trc	100	-	120	-	150	-	nS
Chip Enable Access Time	TCE	-	100	-	120	-	150	nS
Address Access Time	TACC	-	100	-	120	-	150	nS
Output Enable Access Time	TOE	-	50	-	60	-	70	nS
OE High to High-Z Output	TDF	-	30	-	30	-	50	nS
Output Hold from Address Change	Тон	0	-	0	-	0	-	nS

Note: $\ensuremath{\mathsf{Vcc}}$ must be applied simultaneously or before $\ensuremath{\mathsf{VPP}}$ and removed simultaneously or after $\ensuremath{\mathsf{VPP}}$.



DC PROGRAMMING CHARACTERISTICS

 $(Vcc = 5.0V \pm 10\%, TA = 25^{\circ} C \pm 5^{\circ} C)$

PARAMETER	SYM.	CONDITIONS	LIMITS		UNIT	
			MIN.	TYP.	MAX.	
Input Load Current	ILI	VIN = VIL or VIH	-10	-	10	μΑ
Vcc Program Current	ICP	CE = VIL	-	-	30	mA
VPP Program Current	IPP	CE = VIL	-	-	30	mA
Input Low Voltage	VIL	-	-0.3	-	0.8	V
Input High Voltage	VIH	-	2.4	-	5.5	V
Output Low Voltage (Verify)	Vol	IOL = 2.1 mA	-	-	0.45	V
Output High Voltage (Verify)	Vон	Iон = -0.4 mA	2.4	-	-	V
A9 Silicon I.D. Voltage	VID	-	11.5	12.0	12.5	V
VPP Program Voltage	VPP	-	11.75	12.0	12.25	V
Vcc Supply Voltage (Program)	VCP	-	4.5	5.0	5.5	V

AC PROGRAMMING/ERASE CHARACTERISTICS

 $(VCC = 5.0V \pm 10\%, TA = 25^{\circ} C \pm 5^{\circ} C)$

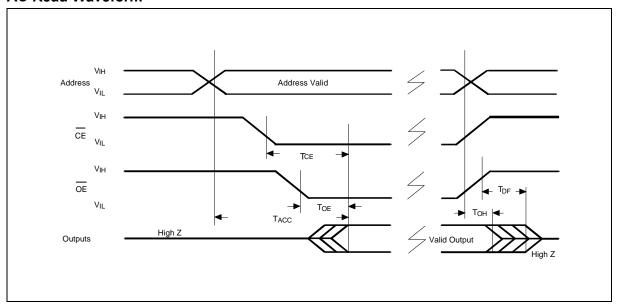
PARAMETER	SYM.	LIMITS			UNIT
		MIN.	TYP.	MAX.	
VPP Setup Time	Tvps	2.0	-	-	μS
Address Setup Time	Tas	2.0	-	-	μS
Data Setup Time	Tos	2.0	-	-	μS
CE Program Pulse Width	TPWP	95	100	105	μS
CE Erase Pulse Width	TPWE	95	100	105	mS
Data Hold Time	TDH	2.0	-	-	μS
OE Setup Time	Toes	2.0	-	-	μS
Data Valid from OE	Toev	-	-	150	nS
OE High to Output High Z	TDFP	0	-	130	nS
Address Hold Time	Тан	0	-	-	μS
Address Hold Time after CE High (Erase)	Танс	2.0	-	-	μS

Note: Vcc must be applied simultaneously or before VPP and removed simultaneously or after VPP.

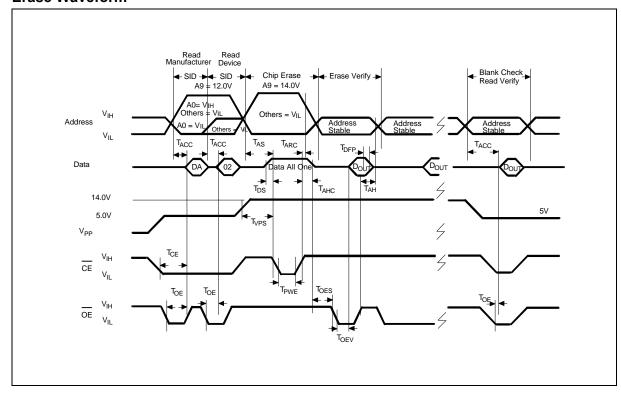


TIMING WAVEFORMS

AC Read Waveform



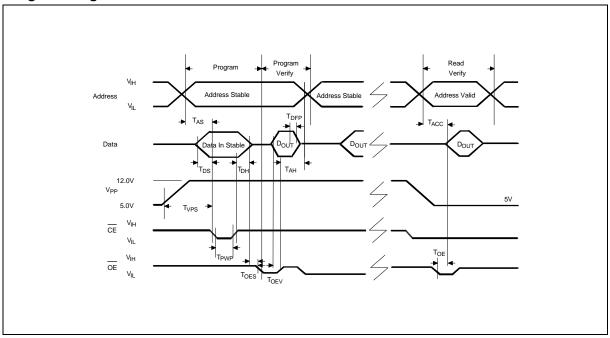
Erase Waveform





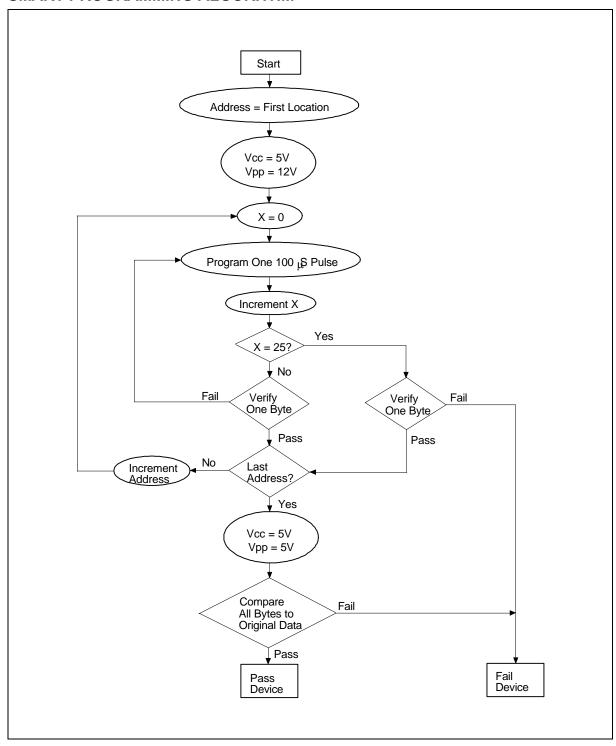
Timing Waveforms, continued

Programming Waveform



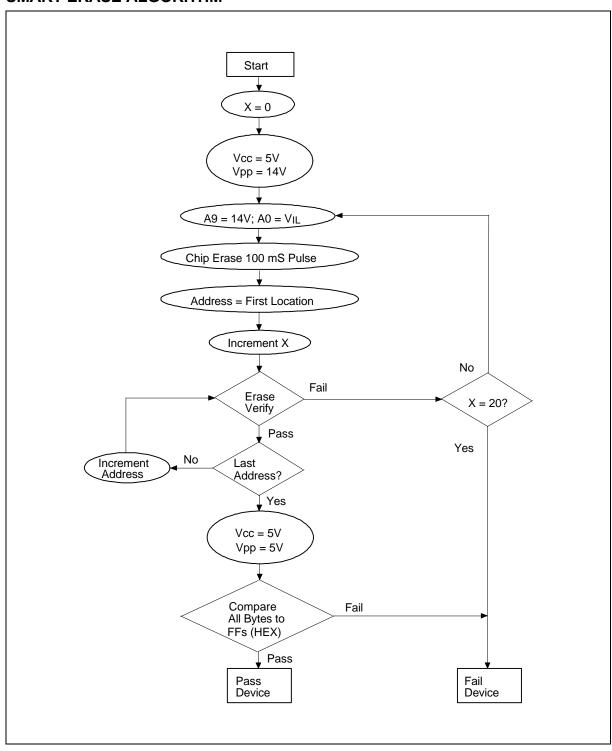


SMART PROGRAMMING ALGORITHM





SMART ERASE ALGORITHM





ORDERING INFORMATION

PART NO.	ACCESS TIME (nS)	POWER SUPPLY CURRENT MAX. (mA)	STANDBY Vcc CURRENT MAX. (µA)	PACKAGE
W27E257-10	100	30	100	600 mil DIP
W27E257-12	120	30	100	600 mil DIP
W27E257-15	150	30	100	600 mil DIP
W27E257P-10	100	30	100	32-pin PLCC
W27E257P-12	120	30	100	32-pin PLCC
W27E257P-15	150	30	100	32-pin PLCC

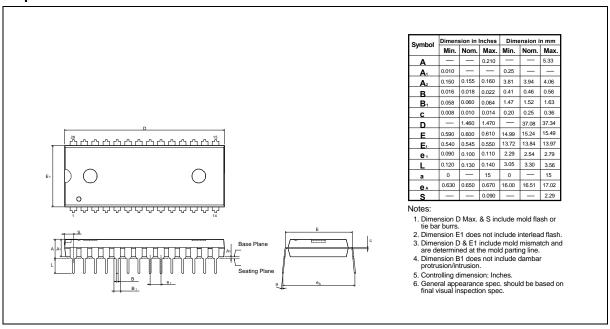
Notes:

- 1. Winbond reserves the right to make changes to its products without prior notice.
- 2. Purchasers are responsible for performing appropriate quality assurance testing on products intended for use in applications where personal injury might occur as a consequence of product failure.

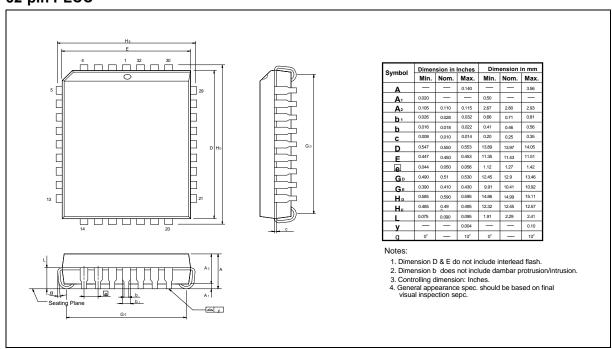


PACKAGE DIMENSIONS

28-pin P-DIP



32-pin PLCC







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Note: All data and specifications are subject to change without notice.